Search Notes				

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/603,300	TAM ET AL.	
Examiner	Art Unit	
Hwei-Siu C. Payer	3724	

SEARCHED				
Class	Subclass	Date	Examiner	
30	393	4 or 6-27-06	Vage.	

INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NO (INCLUDING SEARCH	TES STRATEGY	)
	DATE	EXMR
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